

# Lec 01

Profiling is a form of dynamic program analysis that measures the space/time complexity of a program to aid program optimization. It could be implemented in H.W.

FPGA: No fabrication needed, limited routing resource.

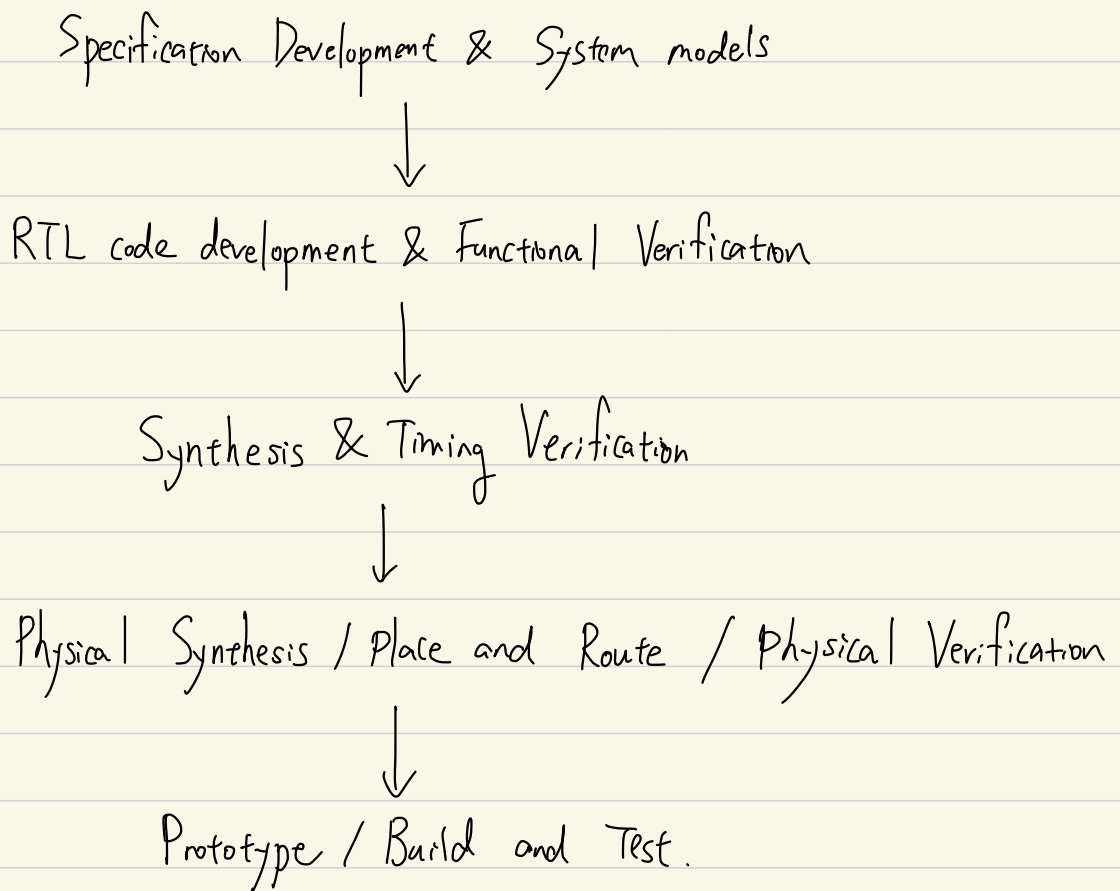
ASIC: • Cell-based Design flow

- use pre-designed logic cells known as standard cells and micro-cells e.g microcontroller.

- Full - Custom Design Flow

- Design everything by yourself.

Cell based Design Flow:



1

Design a Calculator

Specify I/O

RTL Code

1. + 2. - 3. x 4. / ...

Write RTL code

Pre-Sim Make sure the calc. is working

Cadence nverilog, irun,  
Synopsys Verdi (nWave)

2.

Choose suitable components from  
standard cell library

Run synthesis by Design  
Compiler

Gate-level  
Netlist

Optimize result and generate  
gate-level Netlist

Gate-Sim Check correctness after adding  
timing info.

3. Floorplan Decide each Components position

Placement Place transistor in best position

Routing Connect ports from different modules

Cadence innovus tool / ...

Layout

Post-Sim Check correctness after adding timing information

Verification Check all function work and no violation Design rule check (DRC)  
Layout versus schematics (Lvs)

↓ Tape Out

Continuous Assignment  $\rightarrow$  for wire assignments.

Procedural Assignment  $\rightarrow$  for reg assignments.

Unsigned / Signed Mix Operation.

- If there's one unsigned operator, the operation would be regarded as unsigned.

```
wire [2:0] a, mod1;  
assign mod1 = a % 7;  
           ↑   ↑   ↑  
           u   u   s  
           ( u s )
```

```
wire [2:0] a;  
wire signed [2:0] mod1;  
assign mod1 = a % 7;  
           *   ↑   ↑  
           s   u   s  
           ( us )
```

```
wire signed [2:0] a;  
wire [2:0] mod1;  
assign mod1 = a % 7;  
           ↑   ↑   ↑  
           *   s   s  
           u   ( s )
```

```
wire signed [2:0] a, mod1;
```

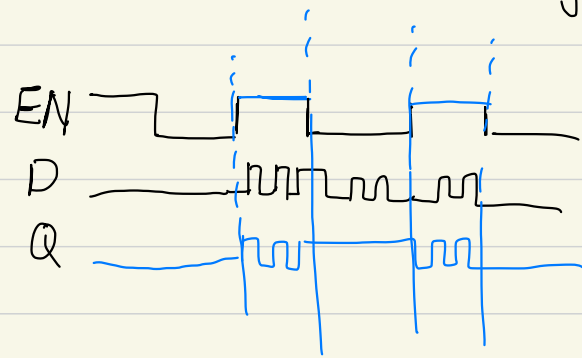
```
assign mod1 = a % 7;  
           ↑   ↑   ↑  
           s   s   s  
           ( s )
```

⚠ May be erroneous.

# Lec 02

Sequential Circuits not only depends on the current input values, but also on preceding input values.

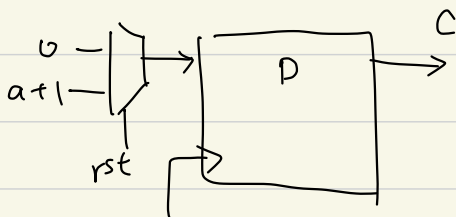
Latch: level sensitive, edge triggered



D Flip-Flop: Edge triggered

## • Synchronous Reset.

```
always @(posedge clk) begin
    if (reset) C <= 0;
    else C <= a+1;
end
```



Pro:

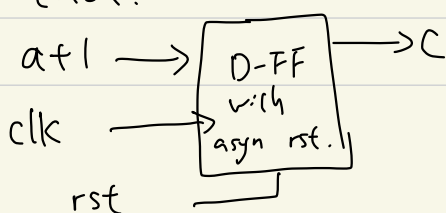
Glitch filtering from reset comb. logic

Con:

- Can't be reset without clk.
- May need pulse stretcher
- Larger Area / Increase critical Path

## • Asynchronous Reset.

```
always @(posedge clk or posedge rst) begin
    if (reset) C <= 0;
    else C <= a+1;
end.
```



Pro: Reset indep. clock signal  
Reset is immediate  
Less Area

Con: Noisy Reset line could cause unwanted reset  
- Metastability.

## For Loop in Verilog.

- Duplicate same function
- Very useful for doing reset and iterated operation.

```
reg [3:0] temp;
integer i;
always @(posedge clk) begin
    for (i=0 ; i < 3 ; i=i+1) begin : for-name
        temp[i] ≤ 1'b0;
    end
end.
```

=

```
always @(posedge clk) begin
    temp[0] ≤ 1'b0;
    temp[1] ≤ 1'b0;
    temp[2] ≤ 1'b0;
end
```

## Generate in Verilog =

```
module A();
endmodule
```

```
module B();
    genvar i;
    generate
        for (i=0 ; i < 3 ; i=i+1) begin
            A uA(...);
        end
    endgenerate
endmodule.
```

⇒

```
module A();
endmodule
```

```
module A();
endmodule
```

```
module A();
endmodule
```

## Mealy machine

- Output depend on the current state and input.
- If input changes, output also changes.

Pro: Less # of states needed

Con: More H.W required for implementation

## Moore machine

- The outputs depend on the current state only.
- Inputs affect outputs but not immediately.

Pro: Safer, Output changes at clock edge

Con: More States required.

# Lec 03

Verification: Demonstrate the functional correctness of a design.  
Testing: Verify the design is manufacturing correctly.

Stages of Verification:

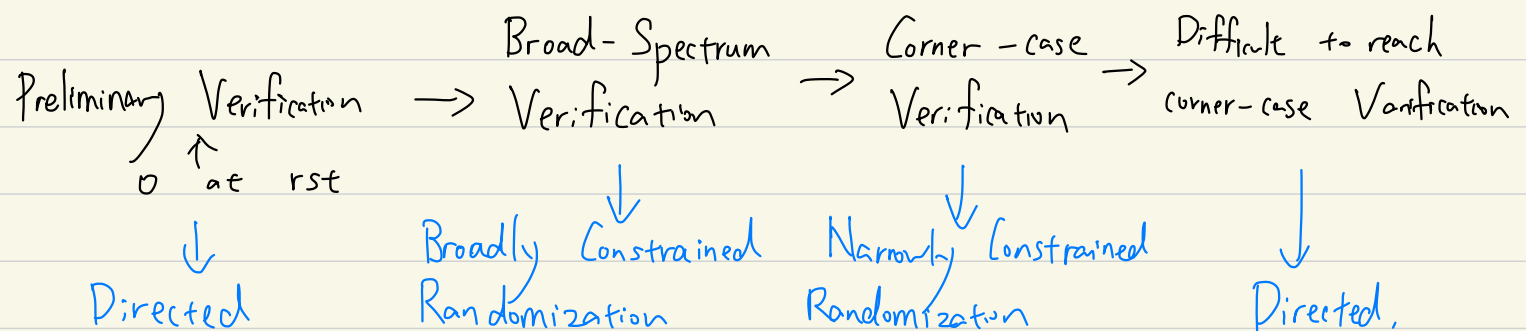
- Preliminary verification  $\rightarrow$  Specification (ex. Output = 0 after rst)
- Broad-Spectrum verification  $\rightarrow$  Test Pattern (ex. Random test)
- Corner-case verification  $\rightarrow$  Special test pattern (ex. Boundary).

Pattern:

Directed Testing  $\rightarrow$  Check what you know

Random Testing  $\rightarrow$  Find what you don't know.

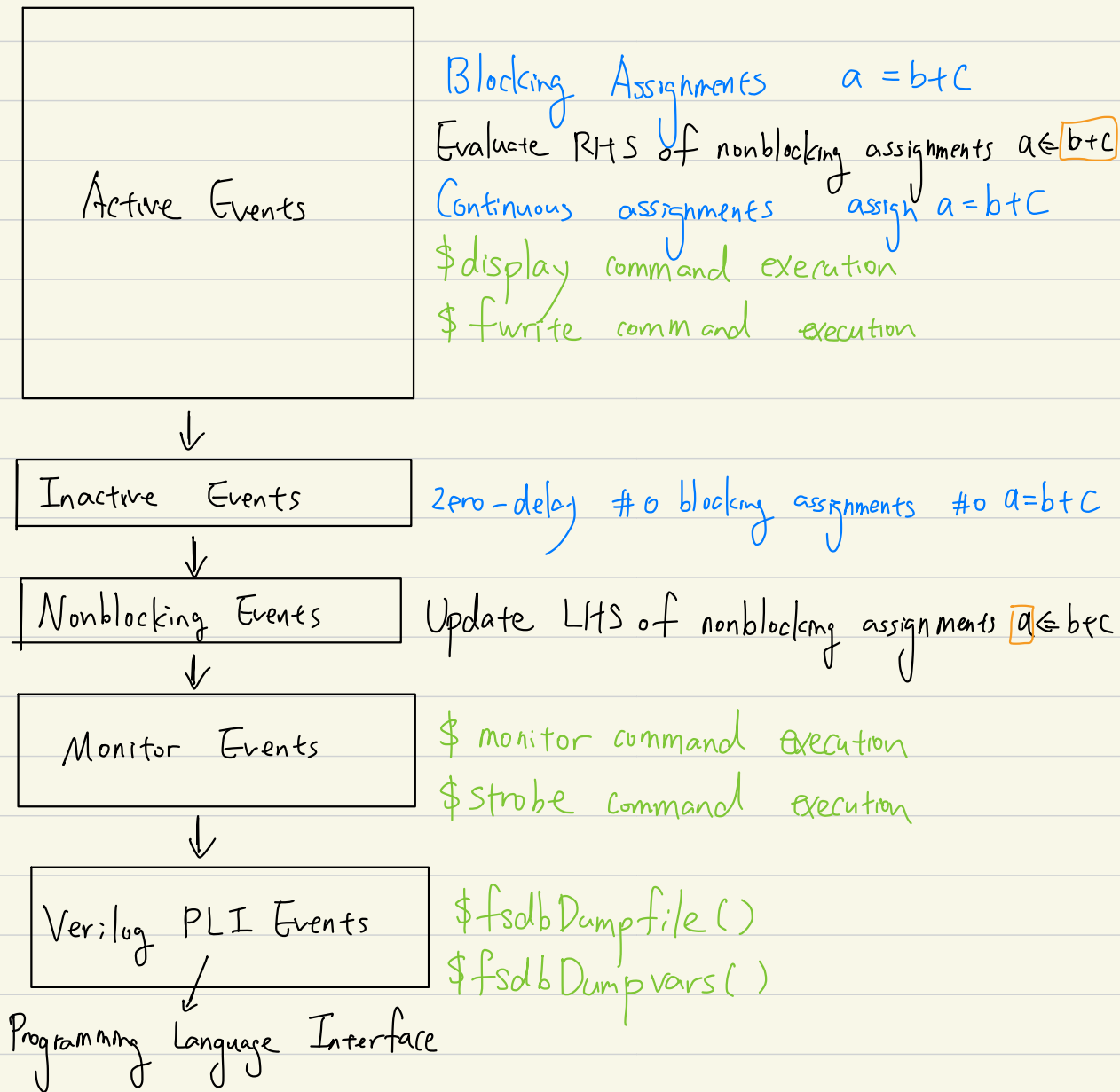
Pattern:



```
integer SEED = 123;          signed
                             ↓
reg [31:0] number;          ( 7)
number = $random( ) % 'd 7;
↑           ↑           ↑
a           a           a
```

# Stratified Event Queue of Verilog.

★ Lec 03 P.24.



Asynchronous reset:

- clock signal should be forced to 0 before reset signal is given.

force clk = 0 ----- release clk;

'timescale : specifies the unit of measurement for time and the degree of precision.

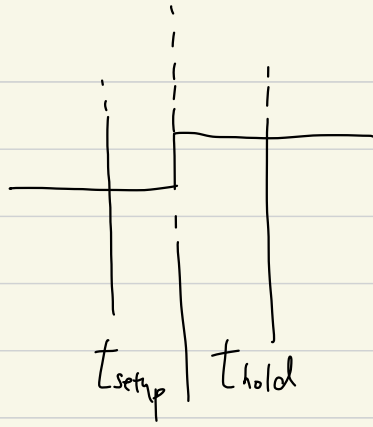
'timescale	Delay	Time Delay
10ns / 1ns	# 5	50ns
10ns / 1ns	# 5.738	57ns
10ns / 10ns	# 5.5	60ns
10ns / 100ps	# 5.738	57.4ns



# Lec 04

- Setup time ( $t_{setup}$ )

- Hold time ( $t_{hold}$ )



## Contamination delay

The minimum amount of time from an input changes until any output starts to change

- CLK-to-Q contamination delay ( $t_{ccq}$ )
- Logic contamination delay ( $t_{cd}$ )

## Propagation delay

The maximum amount of time from input changes until all output reaches steady state.

- CLK-to-Q propagation delay ( $t_{pcq}$ )
- Logic propagation delay ( $t_{pd}$ )

## Setup Time Criterion

### Setup Time Check:

- data Required Time :  $T_{cyc} + T_{skew} - t_{setup}$
- data arrival Time :  $t_{pcq} + t_{pd}$
- Slack = data required time - data arrival time.

## Hold Time Criterion

- data required time =  $t_{skew} + t_{hold}$
- data arrival time =  $t_{ccq} + t_{cd}$
- Slack = data arrival time - data required time

Pipelining doesn't help latency of single task, but throughput of entire.  
Pipeline rate are limited by the slowest stage.

## IP (Intellectual Property)

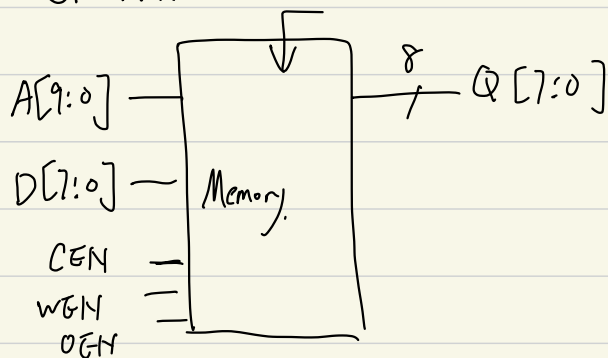
- Hard IP : GDSII Format , high performance but technology dependent.
- Firm IP : Netlist resource , less used.
- Soft IP : RTL design , requires verification.

# Lec 05

## SRAM

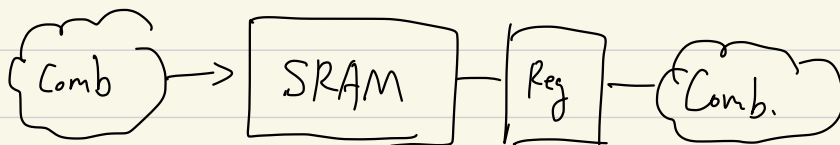
- Read / Write Data only
- Memory has less area than registers
- Memory is slower than registers.
- Only one address

## SRAM.



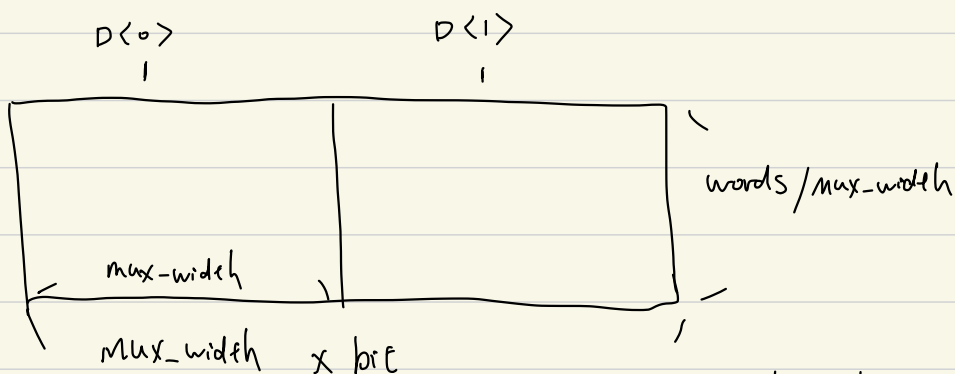
$CEN$ : Chip enable negative  
 $OEN$ : Output enable negative  
 $WEN$ : Write enable negative

To avoid critical path causing timing violations:  
Add registers after the hard macro.



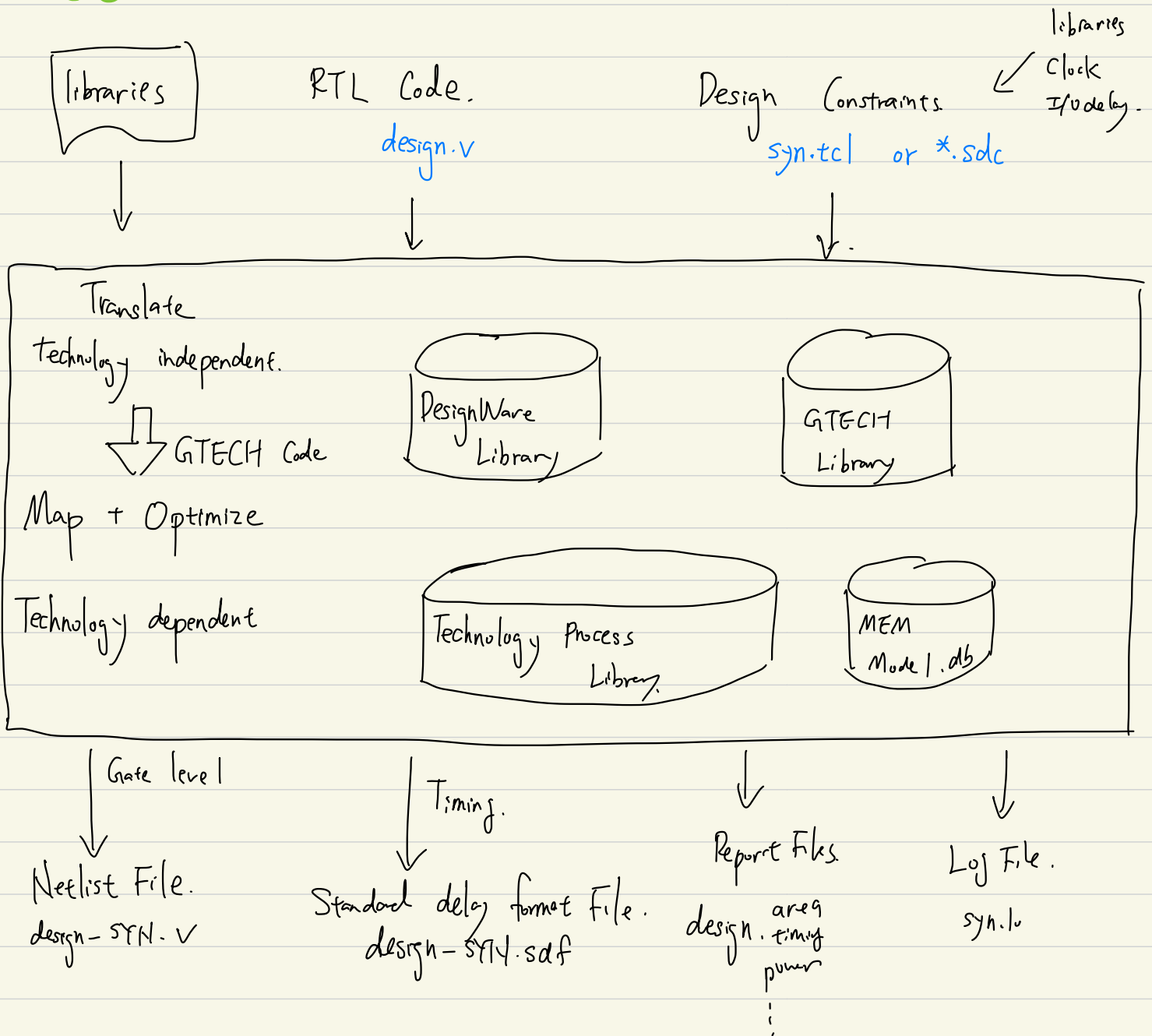
## Memory Compiler.

64 words, 2 bit, mux-wid = 16



$$\Rightarrow \text{mux-width} \times \text{bit} = \text{words} \div \text{mux-width}$$

# Lec 06



Develop HDL files.



Specify Libraries.

① Synthetic Lib : additional DW lib for optimization

② Link lib : list of libs Design Compiler could use to resolve design ref.

③ Target lib : Includes timings.

link-library synthetic-library target-library



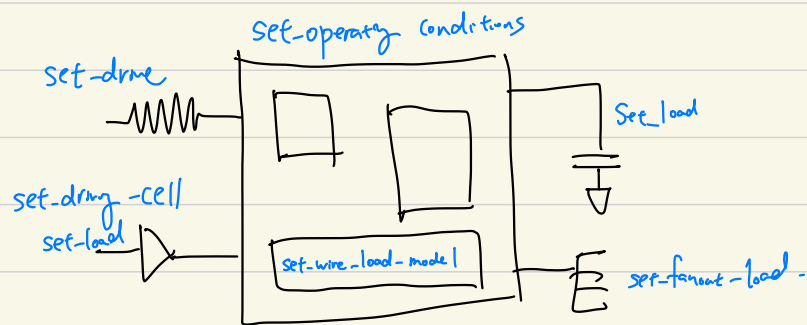
Read Design

read-file , read-sverilog  
analyze -f , elaborate



Develop Design Environment

Define the environment in which the design is expected to operate in by specifying operating conditions, wire load models, system interface,



Before APR, wire load models can be used to estimate cap. resis. and area overhead, top, enclosed, segmented.



# Set Design Constraints

## Design Rule Constraints

- reflects technological - specific constraints. must hold

- set - ideal - network {clk, rst-n}

## Design optimization Constraints.

- user defines speed (timing) and area optimization goals for the design compiler.

- create - clock